TENTATIVE

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC7WH245FU, TC7WH245FK

(UNDER DEVELOPMENT)

DUAL BUS TRANSCEIVER

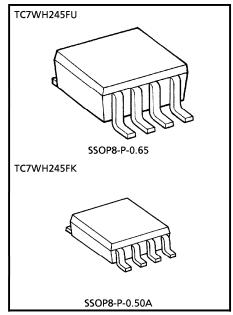
The TC7WH245 is an advanced high speed CMOS DUAL BUS TRANSCEIVER fabricated with silicon gate CMOS technology. It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

It is intended for two-way asynchronous communication between data busses. The direction of data transmission is determined by the level of the DIR input.

The enable input (\overline{G}) can be used to disable the device so that the busses are effectively isolated.

All inputs are equipped with protection circuits against static discharge.

FEATURES



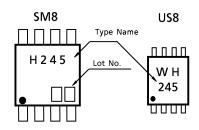
Weight

SSOP8-P-0.65 : 0.02g (Typ.) SSOP8-P-0.50A : 0.01g (Typ.)

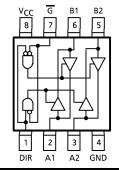
APPLICATION NOTES

- 1) Do not apply a signal to any bus terminal when it is in the output mode. Damage may result.
- 2) All floating (high impedance) bus terminals must have their input levels fixed by means of pull up or pull down resistors or bus terminator IC's such as the TOSHIBA TC40117BP.
- 3) A parasitic diode is formed between the bus and V_{CC} terminals. Therefore bus terminal can not be used to interface 5V to 3V systems directly.

MARKING



PIN ASSIGNMENT (TOP VIEW)



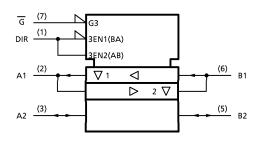
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MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Supply Voltage Range	Vcc	-0.5~7.0	V	
DC Input Voltage	V _{IN}	-0.5~7.0	٧	
DC Output Voltage	Vout	-0.5~V _{CC} + 0.5	٧	
Input Diode Current	ΙK	– 20	mA	
Output Diode Current	^I ок	± 20	mA	
DC Output Current	lout	± 25	mA	
DC V _{CC} / Ground Current	lcc	± 50	mΑ	
Bayyar Dissination	D-	300 (SM8)	mW	
Power Dissipation	PD	200 (US8)	IIIVV	
Storage Temperature	T _{stg}	-65∼150	°C	
Lead Temperature (10 s)	TL	260	°C	

LOGIC DIAGRAM



TRUTH TABLE

INP	UTS	FUNC	OUTPUT	
G	DIR	A BUS B BUS		001101
L	L	OUTPUT	INPUT	A = B
L	Н	INPUT OUTPUT		B = A
Н	×	High im	Z	

x : Don't care Z : High impedance

RECOMMENDED OPERATING CONDITIONS

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Supply Voltage	Vcc	2.0~5.5	V	
Input Voltage	VIN	0~5.5	V	
Output Voltage	Vout	0~V _{CC}	V	
Operating Temperature	T _{opr}	- 40∼8 5	°C	
Input Rise and Fall Time	dt/dv	$0 \sim 100 \text{ (V}_{CC} = 3.3 \pm 0.3 \text{V)}$	ns / V	
input Rise and Fail Time	at/av	$0\sim20 \ (V_{CC}=5\pm0.5V)$] 115 / V	

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The information contained herein is subject to change without notice.

DC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC SYME		DL TEST CONDITION		Vcc	Ta = 25°C			Ta = -4	UNIT	
CHARACTERISTIC	SYMBOL	TEST CONDITION		V _C C (V)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
High-Level			2.0	1.50	_	_	1.50	_		
Input Voltage	V _{IH}	_		3.0~ 5.5	V _C C ×0.7	_	_	V _C C ×0.7	_	V
Low-Level				2.0		_	0.50	_	0.50	
Input Voltage	V _{IL}	_		3.0~ 5.5	_	-	V _C C × 0.3	_	V _{CC} ×0.3	V
				2.0	1.9	2.0	_	1.9	_	
High-Level		V _{IN} = V _{IH} or V _{IL}	$I_{OH} = -50\mu A$	3.0	2.9	3.0		2.9	_	
Output Voltage	Voн			4.5	4.4	4.5		4.4	_	V
Cutput Voltage			$I_{OH} = -4mA$	3.0	2.58	1		2.48	_	
			$I_{OH} = -8mA$	4.5	3.94	1		3.80	_	
		V _{IN} = V _{IH} or V _{IL}	Ι _{ΟL} = 50μΑ	2.0		0.0	0.1	_	0.1	٧
Low-Level				3.0	_	0.0	0.1	_	0.1	
Output Voltage	VOL			4.5		0.0	0.1	_	0.1	
Cutput Voltage			$I_{OL} = 4mA$	3.0		1	0.36	_	0.44	
			I _{OL} = 8mA	4.5		1	0.36	_	0.44	
3-State Output Off-State Current	loz	V _{IN} = V _{IH} or V _{IL} V _{OUT} = V _{CC} or GND		5.5	-	1	± 0.25	_	± 2.5	μ A
Input Leakage Current	IIN	V _{IN} = 5.5V or GND		0~ 5.5			± 0.1		± 1.0	μΑ
Quiescent Supply Current	lcc	V _{IN} = V _{CC} or GND		5.5	_	_	2.0	_	20.0	μΑ

CHARACTERISTIC SVA		TEST CONDITION		J	Ta = 25°C			Ta = −40~85°C		LINIT
CHARACTERISTIC	SYMBOL		V _{CC} (V) C		MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
Propagation Delay	t _{pLH}		3.3 ± 0.3	15	_	5.8	8.4	1.0	10.0	
			3.3 ± 0.3	50	_	8.3	11.9	1.0	13.5	nc
Time	t _{pHL}		5.0 ± 0.5	15	_	4.0	5.5	1.0	6.5	ns
			3.0 ± 0.5	50	_	5.5	7.5	1.0	8.5	
	$ P^{} R_1 = R_2 \rangle$	3.3 ± 0.3	15		8.5	13.2	1.0	15.5		
3-State Output Enable Time		$R_L = 1k\Omega$	3.3 ± 0.3	50		11.0	16.7	1.0	19.0	nc
			5.0 ± 0.5	15	_	5.8	8.5	1.0	10.0	ns
	-		3.0 ± 0.5	50	_	7.3	10.6	1.0	12.0	
3-State Output	^t pLZ	$R_L = 1k\Omega$	3.3 ± 0.3	50	_	11.5	15.8	1.0	18.0	25
Disable Time	t _{pHZ}	K = 1K22	5.0 ± 0.5	50	_	7.0	9.7	1.0	11.0	ns
Output to Output	tosLH	(Note 1)	3.3 ± 0.3	50	_	_	1.5	-	1.5	25
Skew	tosHL	(Note 1)	5.0 ± 0.5	50	_	_	1.0	_	1.0	ns
Input Capacitance	CIN	DIR, G			_	4	10	_	10	рF
Bus Input Capacitance	C _I /O	An, Bn			_	8	_	_	_	рF
Power Dissipation Capacitance	C _{PD}	(Note 2)				21	_	_	_	pF

(Note 1) : Parameter guaranteed by design. $t_{OSLH} = |t_{pLHm} - t_{pLHn}|$, $t_{OSHL} = |t_{pHLm} - t_{pHLn}|$ (Note 2) : CPD is defined as the value of the internal equivalent capacitance which is

calculated from the operating current consumption without load.

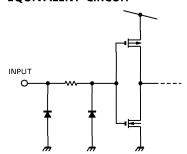
Average operating current can be obtained by the equation :

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2 \text{ (per bit)}$

NOISE CHARACTERISTICS (Ta = 25°C, Input $t_r = t_f = 3ns$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	V _{CC} (V)	TYP.	IMIT	UNIT
Quiet Output Maximum Dynamic V _{OL}	V _{OLP}	C _L = 50pF	5.0	0.5	0.8	٧
Quiet Output Minimum Dynamic V _{OL}	V _{OLV}	C _L = 50pF	5.0	- 0.5	-0.8	V
Minimum High Level Dynamic Input Voltage	VIHD	C _L = 50pF	5.0	_	3.5	V
Maximum Low Level Dynamic Input Voltage	V _{ILD}	C _L = 50pF	5.0		1.5	٧

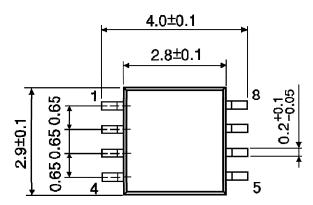
INPUT EQUIVALENT CIRCUIT

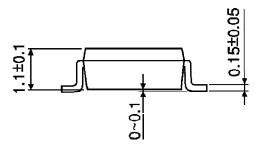


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OUTLINE DRAWING SSOP8-P-0.65

Unit: mm

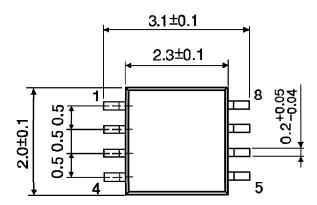


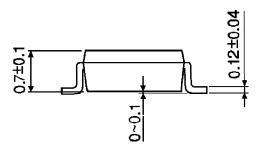


Weight: 0.02g (Typ.)

OUTLINE DRAWING SSOP8-P-0.50A

Unit: mm





Weight: 0.01g (Typ.)